


<b>Search Notes</b>  	<b>Application/Control No.</b>  10578514	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG-HAE ET AL.
	<b>Examiner</b>  Matthew E Hoban	<b>Art Unit</b>  1793

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
See East Search History	8/27/08	meh
Searched truncation via WEST	8/27/08	meh
Searched Google Scholar	8/27/08	meh
Inventor Search completed through PALM	8/27/08	meh
Updated East Search	03/05/08	mh

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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